Lecture #20		
OUTLINE		
• Th - • Lo • Di • Di	ne pn junction (cont'd) reverse breakdown bad line analysis method iode models iode applications	
	Reference Reading	
	• Rabaey et al. (finish Chapter 3.2)	
	 Howe & Sodini 	
	– Chapter 6.4.1 - 6.4.2	
	 Schwarz and Oldham (finish Chapter 13.2) 	
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